

SMART DIMM Reliability Equates to Test

With its advanced testing services that include the combination of ATE and system testing SMART offers high reliability modules targeted for mission-critical applications. By testing all the module circuitry and its components as well as how the assembled modules function at full speed operation in a system this method offer proven reliability.

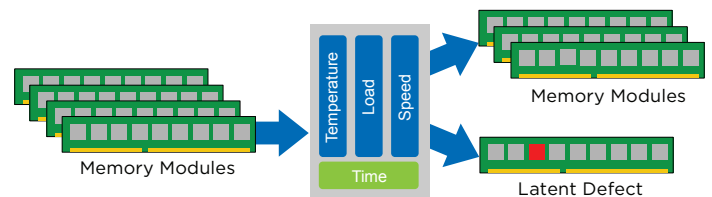
Phase 1: ATE - Automated Test Equipment

- Industry standard test platform for testing high volumes in factory environment. Very effective at finding high level defects.
- DC parametric testing
 - Continuity, Shorts, Input/output leakage, power
- AC functional tests
 - Mode (check basic read/write, DM)
 - Timing (broad range of March tests)
 - Data patterns
 - VDD/VREF (low/nominal/high – with margin)
 - Data retention (extensive testing)



Phase 2: SLT - System Level Testing

- Finds defects by testing in an application environment
 - Testing in a motherboard cannot be replicated with ATE
- SLT performed on Intel based motherboards
 - High memory utilization (<2% idle time)
 - Full rated module speed (DDR4-3200)
- Failures identified include:
 - No boot
 - Single and multibit ECC
 - Performance / speed
 - Wear DRAM cells
- SMART performs 100% ATE test AND 100% System Level Test (SLT)



Headquarters/North America:

T: (+1) 800-956-7627 • T: (+1) 510-623-1231
F: (+1) 510-623-1434 • E: info@smartm.com

Latin America:

T: (+55) 11 4417-7200 • E: sales.br@smartm.com

Asia/Pacific:

T: (+65) 6678-7670 • E: sales.asia@smartm.com

EMEA:

T: (+44) 0 7826-064-745 • E: sales.euro@smartm.com

Customer Service:

T: (+1) 510-623-1231 • E: customers@smartm.com